

P-Channel 80 V (D-S) MOSFET

DESCRIPTION

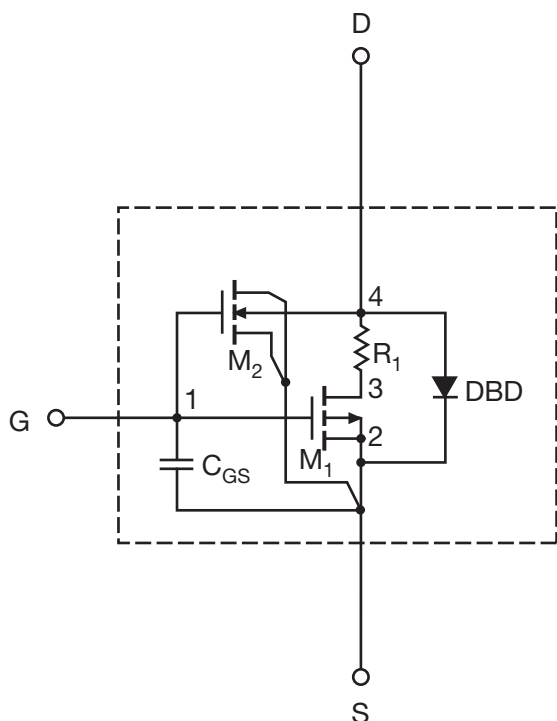
The attached SPICE model describes the typical electrical characteristics of the p-channel vertical DMOS. The subcircuit model is extracted and optimized over the - 55 °C to 125 °C temperature ranges under the pulsed 0 V to 10 V gate drive. The saturated output impedance is best fit at the gate bias near the threshold voltage.

A novel gate-to-drain feedback capacitance network is used to model the gate charge characteristics while avoiding convergence difficulties of the switched C_{gd} model. All model parameter values are optimized to provide a best fit to the measured electrical data and are not intended as an exact physical interpretation of the device.

CHARACTERISTICS

- P-Channel Vertical DMOS
- Macro Model (Subcircuit Model)
- Level 3 MOS
- Apply for both Linear and Switching Application
- Accurate over the - 55 °C to + 125 °C Temperature Range
- Model the Gate Charge, Transient, and Diode Reverse Recovery Characteristics

SUBCIRCUIT MODEL SCHEMATIC



Note

- This document is intended as a SPICE modeling guideline and does not constitute a commercial product datasheet. Designers should refer to the appropriate datasheet of the same number for guaranteed specification limits.



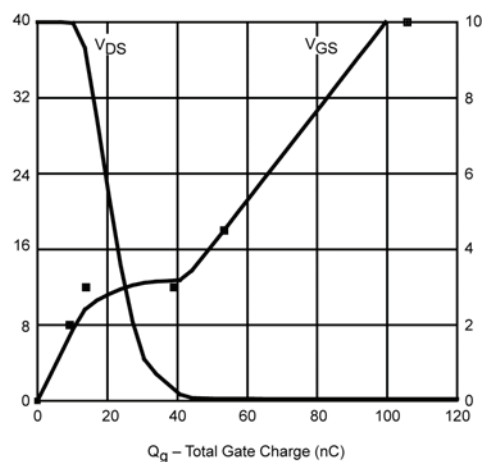
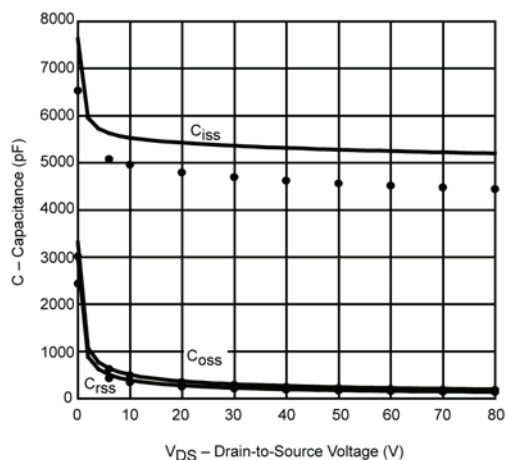
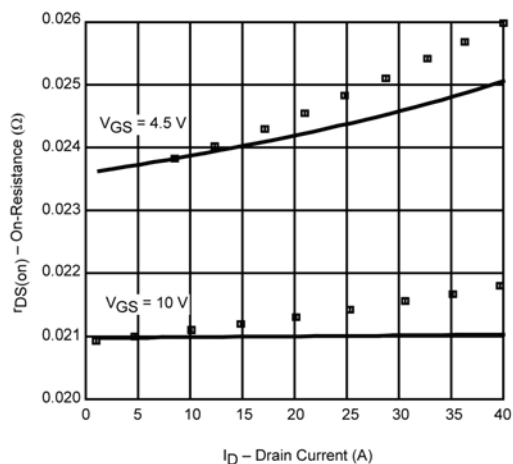
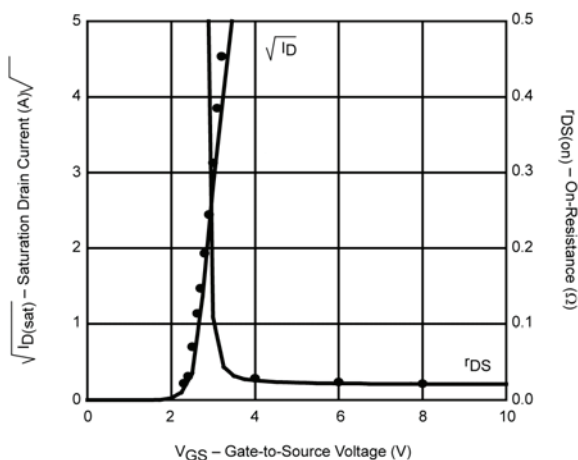
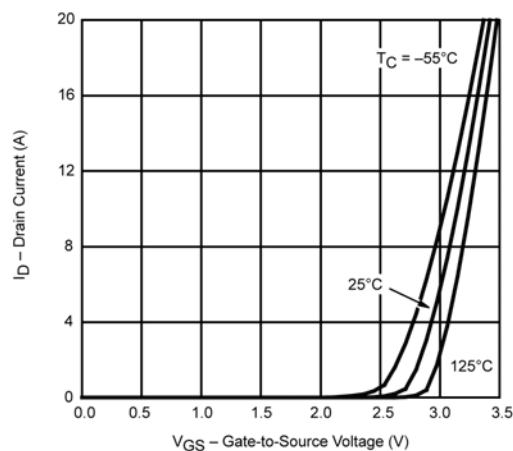
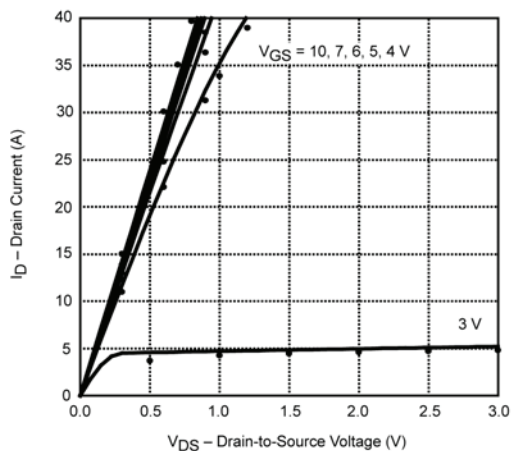
SPECIFICATIONS ($T_J = 25^\circ\text{C}$, unless otherwise noted)					
PARAMETER	SYMBOL	TEST CONDITIONS	SIMULATED DATA	MEASURED DATA	UNIT
Static					
Gate Threshold Voltage	$V_{GS(th)}$	$V_{DS} = V_{GS}$, $I_D = -250\ \mu\text{A}$	2	-	V
On-State Drain Current ^a	$I_{D(on)}$	$V_{DS} = -5\ \text{V}$, $V_{GS} = -10\ \text{V}$	234	-	A
Drain-Source On-State Resistance ^a	$R_{DS(on)}$	$V_{GS} = -10\ \text{V}$, $I_D = -10.2\ \text{A}$	0.021	0.021	Ω
		$V_{GS} = -4.5\ \text{V}$, $I_D = -8.1\ \text{A}$	0.024	0.024	
Forward Transconductance ^a	g_{fs}	$V_{DS} = -15\ \text{V}$, $I_D = -10.2\ \text{A}$	33	30	S
Diode Forward Voltage	V_{SD}	$I_S = -8.1\ \text{A}$	-0.86	-0.80	V
Dynamic^b					
Input Capacitance	C_{iss}	$V_{DS} = -40\ \text{V}$, $V_{GS} = 0\ \text{V}$, $f = 1\ \text{MHz}$	5320	4700	pF
Output Capacitance	C_{oss}		272	320	
Reverse Transfer Capacitance	C_{rss}		198	235	
Total Gate Charge	Q_g	$V_{DS} = -40\ \text{V}$, $V_{GS} = -10\ \text{V}$, $I_D = -10.2\ \text{A}$	108	105	nC
			55	55	
Gate-Source Charge	Q_{gs}	$V_{DS} = -40\ \text{V}$, $V_{GS} = -4.5\ \text{V}$, $I_D = -10.2\ \text{A}$	16	16	
Gate-Drain Charge	Q_{gd}		26	26	

Notes

- a. Pulse test; pulse width $\leq 300\ \mu\text{s}$, duty cycle $\leq 2\ \%$.
b. Guaranteed by design, not subject to production testing.



COMPARISON OF MODEL WITH MEASURED DATA ($T_J = 25^\circ\text{C}$, unless otherwise noted)



Note

- Dots and squares represent measured data.